	Hits	Search Text	DBs
29	5	((selective$5 or response or signal$4 or (defect near9 portion)) same (sensor or detect$4 or interferomet$4 or SEM) same (mitigat$4 or reduc$4 or decreas$4 or monitor$4 or reflow or (thermal near5 reflow) or RELACS or SAFIER or post$4heat$4 or heat$4) same (line$3dege$3roughness or ((edge or side$4) near12 roughnes$4) or LER or (line$3 near3 edge near4 roughnes$3)) same (pattern or ((resist or photoresist or photosensitive) near9 (structure or pattern$4 or feature))))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
30	14	((selective$5 or response or signal$4 or (defect near9 portion)) same (sensor or detect$4 or interferomet$4 or SEM) same (mitigat$4 or reduc$4 or decreas$4 or monitor$4 or reflow or (thermal near5 reflow) or RELACS or SAFIER or post$4heat$4 or heat$4) same (pattern or ((resist or photoresist or photosensitive) near9 (structure or pattern$4 or feature)))) and ((trim$6 or etch$5 or CMP or PEB or post$5bak or bak$5) same (asymmetr$5 or deviat$5 or varia$5 or difference) same (pattern or profile or feature or CD or LER) same (photoresist or resist) same correct$5)	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB